

A new estimator for quantile-oriented sensitivity indices

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April 19th, 2016, Les Houches

Sensitivity Analysis - Introduction

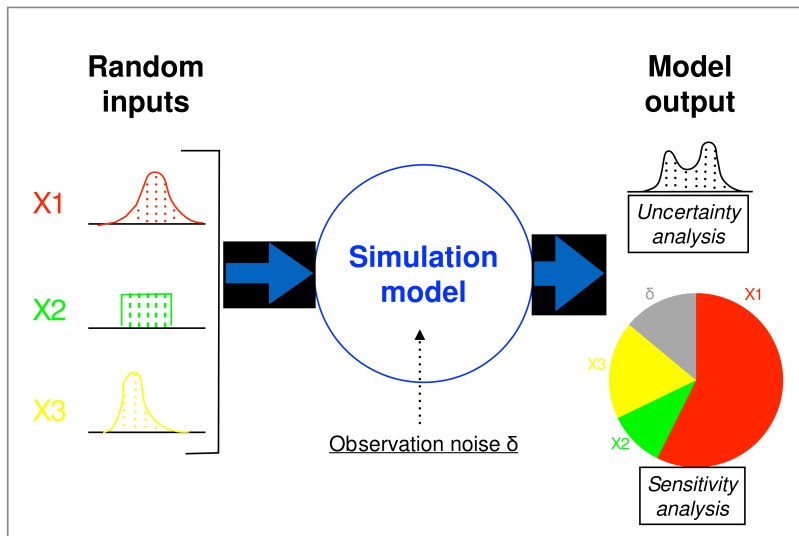
- Numerical code g .
- **Random inputs** $(X_1, \dots, X_d) \sim (f_1, \dots, f_d)$ *iid*.

- **Random output** $Y \in \mathbb{R}$ such that

$$Y = g(X_1, \dots, X_d).$$

- **Main goal** : for $i \in \{1, \dots, d\}$, how does X_i 's uncertainty propagate through g ?

Sensitivity analysis - Schema



Sensitivity analysis

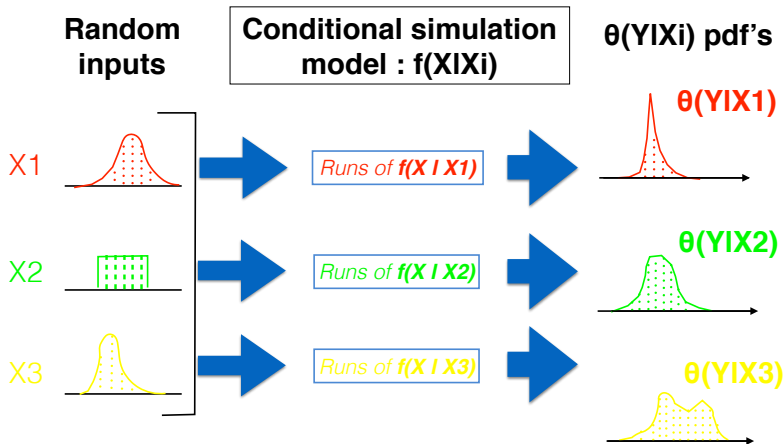
- Several potential uses :
 - Better **understanding** of the model,
 - Neglect X_i 's distribution if not **influential**,
 - Feedback on the inputs - reducing X_i 's distribution if too much **influential**.
- **Global analysis** : most relevant way ?

Goal-oriented sensitivity analysis

- In practice, Y 's distribution does not need to be fully known.
- Choice of a probability feature $\theta(Y)$ (mean, quantiles etc ...) which may be relevant.
- Goal-oriented sensitivity analysis (GOSA) [N. Rachdi, 2011] :
→ For $i \in \{1, \dots, d\}$, quantification of X_i 's influence over $\theta(Y)$.

- **One by one strategy** : condition the code g by X_i and compute $\theta(Y | X_i)$
Set x_i realization of $X_i \rightarrow g(X_1, \dots, x_i, \dots, X_d) \rightarrow \theta(Y | X_i = x_i)$,
Condition g by all the possible values x_i , regarding f_i :
 $\rightarrow \theta(Y | X_i)$'s **distribution**, random variable function of X_i .

Respective influences of each input over $\theta(Y)$



Contrast functions

- Use **contrast functions** to quantify $\theta(Y | X_i)$'s variability.
- **Simple contrasts** : $\forall (y, \theta) \in \mathbb{R}^2 \quad \varphi(y, \theta) \geq 0$
quantify a "distance" between two real components.
- **Mean contrasts** : for Y r.r.v. $\phi_Y(\theta) = \mathbb{E}_Y[\varphi(Y, \theta)]$.
- **Y 's feature** : $\theta(Y) := \arg \min_{\theta \in \mathbb{R}} \phi_Y(\theta)$.

Contrast functions : mean and quantiles

- If $\varphi(y, \theta) = m(y, \theta) = |y - \theta|^2$:

therefore $\phi_Y(\theta) = \mathbb{E}_Y[|Y - \theta|^2]$,

→ $\theta(Y) = \mathbb{E}[Y]$.

- If, for $\alpha \in]0; 1[$, $\varphi(y, \theta) = c_\alpha(y, \theta) = (y - \theta)(\alpha - 1_{y \leq \theta})$:

therefore $\phi_Y(\theta) = \mathbb{E}_Y[(Y - \theta)(\alpha - 1_{Y \leq \theta})]$,

→ $\theta(Y) = q^\alpha(Y)$, α -quantile de Y .

- We focus on $\varphi = c_\alpha$: $\theta(Y) = q^\alpha(Y)$.

N.B. :

$$\min_{\theta} \phi(\theta | X_i = x_i) = \mathbb{E}[c_\alpha(Y, q^\alpha(Y | X_i)) | X_i = x_i].$$

Sensitivity analysis with respect to a contrast

- Need to quantify the **variability** of $\theta(Y | X_i)$.
- Sensitivity indices based on **contrasts** [Fort et al., 2013]

$$S_{\varphi}^{X_i}(Y) = \min_{\theta \in \mathbb{R}} \phi_Y(\theta) - \mathbb{E} \left[\min_{\theta \in \mathbb{R}} \phi_Y(\theta | X_i) \right].$$

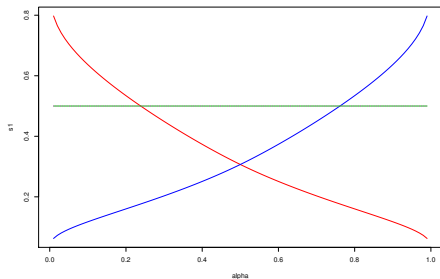
→ quantifies the influence of the input X_i on $\theta(Y)$.

- $S_{\varphi}^{X_i}(Y) \geq 0$.
- We divide $S_{\varphi}^{X_i}(Y)$ by $\min_{\theta \in \mathbb{R}} \phi_Y(\theta)$ so that $0 \leq S_{\varphi}^{X_i}(Y) \leq 1$.

$$S_{C_{\alpha}}^i(Y) = 0 \Leftrightarrow \theta(Y | X_i) = \theta(Y) \text{ a.s.}$$

$$S_{C_{\alpha}}^i(Y) = 1 \Leftrightarrow (Y | X_i = x_i) = \text{constant}(x_i) \text{ a.s.}$$

Sensitivity analysis with respect to a contrast



- $Y = X_1 + X_2$
with $X_1 \sim \text{Exp}(1)$ and $X_2 \sim -\text{Exp}(1)$
independent.
- $S_m^{X_1} = S_m^{X_2} = 0.5$ (Sobol indices).
- Both inputs are **influential on the mean** $\mathbb{E}[Y]$!
- $S_{c_\alpha}^{X_1}$: X_1 's influence on Y 's α -quantile.
- $S_{c_\alpha}^{X_2}$: X_2 's influence on Y 's α -quantile.
- Sensitivity changes regarding the level of quantile α .

Estimation of the quantile-oriented index

- **Goal** : from a n -sample $(X_i^1, Y^1), \dots, (X_i^n, Y^n)$, estimation of

$$\begin{aligned} S_{c_\alpha}^{X_i}(Y) &= \min_{\theta} \phi_Y(\theta) - \mathbb{E} \left[\min_{\theta \in \mathbb{R}} \phi_Y(\theta \mid X_i) \right]. \\ &= \mathbb{E} [c_\alpha(Y, q^\alpha(Y))] - \mathbb{E}_{X_i} \left[\min_{\theta \in \mathbb{R}} \mathbb{E} [c_\alpha(Y, \theta) \mid X_i] \right]. \end{aligned}$$

- 1st term estimation :

$$\min_{\theta} \frac{1}{n} \sum_{j=1}^n c_\alpha(Y^j, \theta) = \frac{1}{n} \sum_{j=1}^n c_\alpha(Y^j, \hat{q}^\alpha(Y)),$$

where $\hat{q}^\alpha(Y)$ is the classical empirical quantile estimator

→ this estimator converges *a.s.*

Estimation for the second term

- Second term : $\mathbb{E}_{X_i} \left[\min_{\theta \in \mathbb{R}} \mathbb{E} [c_\alpha(Y, \theta) \mid X_i] \right]$.
- Several issues :
 - Double expectation
 - Conditional expectation
 - Minimization problem.
- We use the following asymptotic result [Fan et al., 1994], for x_i any possible realization of X_i :

$$\arg \min_{\theta} \frac{1}{f_i(x_i)} \sum_{j=1}^n c_\alpha(Y^j, \theta) K_{h(n)}(X_i^j - x_i) \xrightarrow[n \rightarrow \infty]{\mathbb{P}} \arg \min_{\theta} \mathbb{E} [c_\alpha(Y, \theta) \mid X_i = x_i],$$

where f_i is the *pdf* of X_i with a compact support, K a 2-order positive kernel and $(h(n))_{n \in \mathbb{N}}$ a bandwidth sequence such that $h(n) \rightarrow 0$ while $n \times h(n) \rightarrow \infty$.

Estimation for the second term

- We define the estimator as :

$$\hat{V}_n = \frac{1}{n} \sum_{k=1}^n \frac{1}{k} \min_{\theta} \frac{1}{f_i(X_i^k)} \sum_{j=1}^k c_{\alpha}(Y^j, \theta) K_{h(k)}(X_i^j - X_i^k)$$

- Useful points :

-As $(\theta \mapsto \sum_{j=1}^k c_{\alpha}(Y^j, \theta) K_{h(k)}(X_i^j - X_i^k))$ is a piecewise linear function whose “angles” are the Y^1, \dots, Y^k

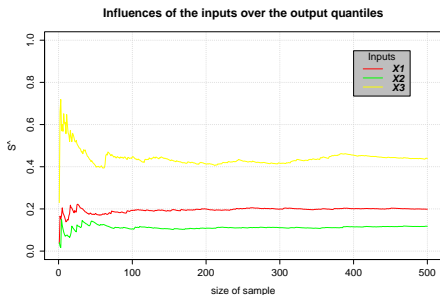
→ its minimizer is among Y^1, \dots, Y^k .

- \hat{V}_n is built **recursively**, ie if we know it, we also know V_1, \dots, V_{n-1} .

- We prove :

$$\hat{V}_n \xrightarrow[n \rightarrow \infty]{\mathbb{P}} \mathbb{E}_{X_i} \left[\min_{\theta} \mathbb{E}[c_{\alpha}(Y, \theta) | X_i] \right].$$

Numerical experiments



- Defect detection : wave control through a structure to study.
- Sensitivity analysis over the random defect a_{90} , function of the inputs X , which we detect with a probability of 90%.
- Influence of the inputs over $q^{0.25}(a_{90})$.
- 3 random inputs :
 - X_1 : the thickness of the structure
 - X_2 : the angle of the control
 - X_3 : the depth of the defect.

Conclusions

- Relevant information for the sensitivity analysis - useful alternative to Sobol indices !
- Estimator not so expensive to compute regarding classical estimators in SA.
- Convergence criterion for \hat{V}_n ?
- **Perspective** : extension to SA over random cumulative distribution functions (ouch !)

Sketch of proof for the consistency

- We define a **parallel “estimator”**, V_n , by substituting the minimum, for each $k \in \{1, \dots, n\}$, by :

$$\frac{1}{f_i(X_i^k)} \sum_{j=1}^k c_\alpha \left(Y^j, q^\alpha \left(Y \mid X^k \right) \right) K_{h(k)} \left(X_i^j - X_i^k \right).$$

- As we express the **increment of $(V_n)_{n \in \mathbb{N}}$** , we get :

$$\forall n \in \mathbb{N}^* \quad \frac{V_n - V_{n-1}}{1/n} = (V^* - V_{n-1}) + \varepsilon(n), \quad \text{where } 1/n \text{ is the time-step}$$

and $\varepsilon(n)$ is a “small enough” residual.

- Let us define a **real function I that interpolates $(V_n)_{n \in \mathbb{N}}$** such that :

$\forall n \in \mathbb{N} \quad I\left(\sum_{k=1}^n 1/k\right) = V_n$. Then :

$$\frac{I\left(\sum_{k=1}^n \frac{1}{k}\right) - I\left(\sum_{k=1}^{n-1} \frac{1}{k}\right)}{1/n} \underset{+\infty}{\sim} \left(V^* - I\left(\sum_{k=1}^{n-1} \frac{1}{k}\right) \right).$$

Sketch of proof for the consistency

- Under the right conditions, the **Kushner-Clark theorem** [3] states that, with a probability of 1, g behaves asymptotically like a solution of the associated $ODE^* : I' = V^* - I$
 $\Rightarrow \lim_{t \rightarrow +\infty} I(t) = V^*$ a.s., since V^* is the limit of every solution of ODE^* .
- This leads to : $V_n \xrightarrow[n \rightarrow \infty]{\mathbb{P}} V^*$.
- By using : $\forall n \in \mathbb{N} \hat{V}_n \leq V_n$ and proving $\mathbb{E} [|V_n - \tilde{V}_n|] \xrightarrow[n \rightarrow \infty]{} 0$
 $\implies \hat{V}_n \xrightarrow[n \rightarrow \infty]{\mathbb{P}} V^*$.



N. Rachdi

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New sensitivity analysis subordinated to a contrast

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Les Houches, c'est bien.

